

# **Ion Beam Handbook for Material Analysis**

**Coordinating Editors**

**J. W. MAYER**

California Institute of Technology  
Pasadena, California

**E. RIMINI**

Istituto di Struttura  
della Materia dell'Università  
Catania, Italy

**Chapter Editors**

B. R. APPLETON

W. K. CHU

L. C. FELDMAN

G. FOTI

J. W. MAYER

I. V. MITCHELL

S. T. PICRAUX

E. RIMINI

J. F. ZIEGLER



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